Acknowledgements

B.13 Uniform Design and Its Industrial Applications
by Kai-Tai Fang, Ling-Yau Chan
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B.14 Cuscore Statistics: Directed Process Monitoring for Early Problem Detection
by Harriet B. Nembhard
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C.19 Statistical Survival Analysis with Applications
by Chengjie Xiong, Kejun Zhu, Kai Yu
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D.28 Measures of Influence and Sensitivity in Linear Regression
by Daniel Peña
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D.29 Logistic Regression Tree Analysis
by Wei-Y. Loh
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D.32 Statistical Genetics for Genomic Data Analysis
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D.34 Statistical Methods In Proteomics
by Weichuan Yu, Baolin Wu, Tao Huang, Xiaoye Li, Kenneth Williams, Hongyu Zhao
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E.39 Cluster Randomized Trials: Design and Analysis
by Mirjam Moerbeek
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E.40 A Two-Way Semilinear Model for Normalization and Analysis of Microarray Data
by Jian Huang, Cun-Hui Zhang
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E.41 Latent Variable Models for Longitudinal Data with Flexible Measurement Schedule
by Haiqun Lin
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E.44 Condition-Based Failure Prediction
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F.50 Six Sigma

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**Yi Li**

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**Mirjam Moerbeek**

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